

Notice of References Cited	Application/Control No. 10/663,774	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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	N	WO 03/058332 A1	07-2003	WIPO	Lee et al.	---
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NON-PATENT DOCUMENTS

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